**DATA SHEET** 

### **General Description**

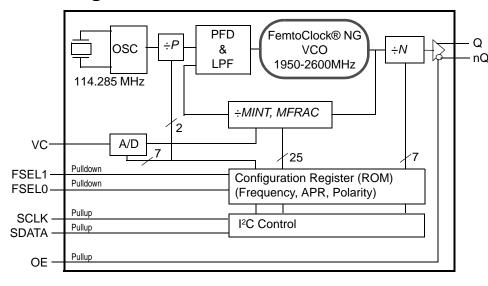
The IDT8N3QV01 is a Quad-Frequency Programmable VCXO with very flexible frequency and pull-range programming capabilities. The device uses IDT's fourth generation FemtoClock® NG technology for an optimum of high clock frequency and low phase noise performance. The device accepts 2.5V or 3.3V supply and is packaged in a small, lead-free (RoHS 6) 10-lead Ceramic 5mm x 7mm x 1.55mm package.

Besides the 4 default power-up frequencies set by the FSEL0 and FSEL1 pins, the IDT8N3QV01 can be programmed via the I²C interface to any output clock frequency between 15.476MHz to 866.67MHz and from 975MHz to 1,300MHz to a very high degree of precision with a frequency step size of 435.9Hz  $\div N$  (N is the PLL output divider). Since the FSEL0 and FSEL1 pins are mapped to 4 independent PLL M and N divider registers (P, MINT, MFRAC and N), reprogramming those registers to other frequencies under control of FSEL0 and FSEL1 is supported. The extended temperature range supports wireless infrastructure, telecommunication and networking end equipment requirements. The device is a member of the high-performance clock family from IDT.

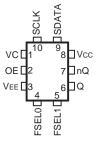
#### **Features**

- Fourth generation FemtoClock® NG technology
- Programmable clock output frequency from 15.476MHz to 866.67MHz and from 975MHz to 1,300MHz
- Four power-up default frequencies (see part number order codes), reprogrammable by I<sup>2</sup>C
- I<sup>2</sup>C programming interface for the output clock frequency, APR and internal PLL control registers
- Frequency programming resolution is 435.9Hz ÷N
- Absolute pull-range (APR) programmable from ±4.5 to ±754.5ppm
- One 2.5V or 3.3V LVPECL differential clock output
- Two control inputs for the power-up default frequency
- LVCMOS/LVTTL compatible control inputs
- RMS phase jitter @ 156.25MHz (12kHz 20MHz): 0.487ps (typical)
- RMS phase jitter @ 156.25MHz (1kHz 40MHz): 0.614ps (typical)
- 2.5V or 3.3V supply voltage modes
- -40°C to 85°C ambient operating temperature
- Available in Lead-free (RoHS 6) package

## **Block Diagram**



## **Pin Assignment**



IDT8N3QV01 Rev G 10-lead Ceramic 5mm x 7mm x 1.55mm package body CD Package Top View

**Table 1. Pin Descriptions** 

Number	Name	Тур	е	Description
1	VC	Input		VCXO Control Voltage input. The control voltage versus frequency characteristics are set by the ADC_GAIN[5:0] register bits.
2	OE	Input	Pullup	Output enable pin. See Table 3A for function. LVCMOS/LVTTL interface levels.
3	V <sub>EE</sub>	Power		Negative power supply.
5, 4	FSEL1, FSEL0	Input	Pulldown	Default frequency select pins. See the Default Frequency Order Codes section. LVCMOS/LVTTL interface levels.
6, 7	Q, nQ	Output		Differential clock output. LVPECL interface levels.
8	V <sub>CC</sub>	Power		Positive power supply.
9	SDATA	Input/Output	Pullup	I <sup>2</sup> C data input. Input: LVCMOS/LVTTL interface levels. Output: Open drain.
10	SCLK	Input	Pullup	I <sup>2</sup> C clock input. LVCMOS/LVTTL compatible interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

**Table 2. Pin Characteristics** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
	Input Canacitanas	FSEL[1:0], SDATA, SCLK		5.5		pF
C <sub>IN</sub>	Input Capacitance	VC		10		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			50		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			50		kΩ

## **Function Tables**

Table 3A. Default Frequency Selection

	Input	
FSEL1	FSEL0	Operation
0 (default)	0 (default)	Default frequency 0
0	1	Default frequency 1
1	0	Default frequency 2
1	1	Default frequency 3

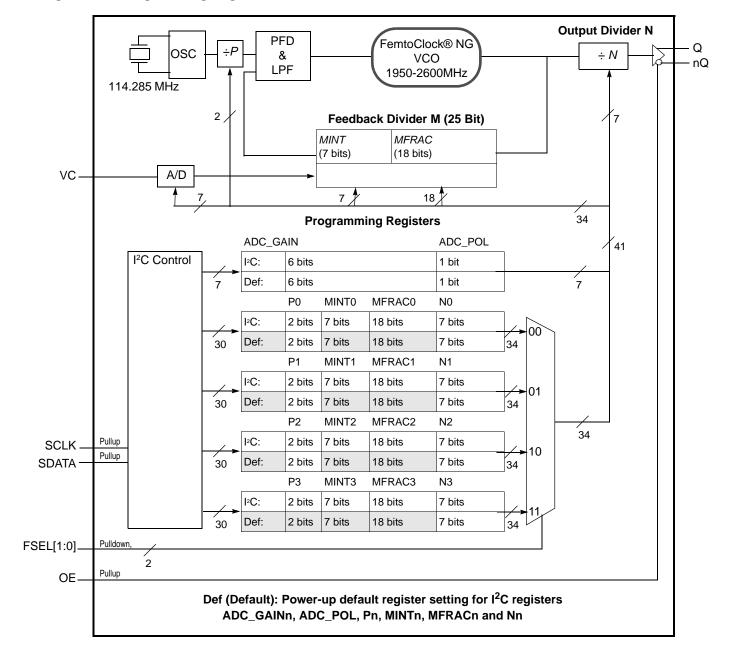
NOTE: The default frequency is the output frequency after power-up. One of four default frequencies is selected by FSEL[1:0]. See programming section for details.

Table 3B. OE Configuration

Input	
OE Output Enable	
0	Outputs Q, nQ are in high-impedance state.
1 (default)	Outputs are enabled.

NOTE: OE is an asynchronous control.

#### **Block Diagram with Programming Registers**



## **Principles of Operation**

The block diagram consists of the internal  $3^{\rm RD}$  overtone crystal and oscillator which provide the reference clock  $f_{\rm XTAL}$  of either 114.285 MHz or 100 MHz. The PLL includes the FemtoClock NG VCO along with the Pre-divider (P), the feedback divider (M) and the post divider (N). The P, M, and N dividers determine the output frequency based on the  $f_{\rm XTAL}$  reference and must be configured correctly for proper operation. The feedback divider is fractional supporting a huge number of output frequencies. The configuration of the feedback divider to integer-only values results in an improved output phase noise characteristics at the expense of the range of output frequencies. In addition, internal registers are used to hold up to four different factory pre-set P, M, and N configuration settings. These default pre-sets are stored in the  $I^2$ C registers at power-up. Each configuration is selected via the the FSEL[1:0] pins and can be read back using the SCLK and SDATA pins.

The user may choose to operate the device at an output frequency different than that set by the factory. After power-up, the user may write new P, N and M settings into one or more of the four configuration registers and then use the FSEL[1:0] pins to select the newly programmed configuration. Note that the I<sup>2</sup>C registers are volatile and a power supply cycle will reload the pre-set factory default conditions.

If the user does choose to write a different P, M, and N configuration, it is recommended to write to a configuration which is not currently selected by FSEL[1:0] and then change to that configuration after the  $I^2C$  transaction has completed. Changing the FSEL[1:0] controls results in an immediate change of the output frequency to the selected register values. The P, M, and N frequency configurations support an output frequency range 15.476MHz to 866.67MHz and 975MHz to 1,300MHz.

The devices use the fractional feedback divider with a delta-sigma modulator for noise shaping and robust frequency synthesis capability. The relatively high reference frequency minimizes phase noise generated by frequency multiplication and allows more efficient shaping of noise by the delta-sigma modulator.

The output frequency is determined by the 2-bit pre-divider (P), the feedback divider (M) and the 7-bit post divider (M). The feedback divider (M) consists of both a 7-bit integer portion (MINT) and an

18-bit fractional portion (MFRAC) and provides the means for high-resolution frequency generation. The output frequency  $f_{OUT}$  is calculated by:

$$f_{OUT} = f_{XTAL} \cdot \frac{1}{P \cdot N} \cdot \left[ MINT + \frac{MFRAC + 0.5}{2^{18}} \right]$$
 (1)

The four configuration registers for the *P, M (MINT & MFRAC)* and *N* dividers which are named Pn, MINTn, MFRACn and Nn with n=0 to 3. "n" denominates one of the four possible configurations.

As identified previously, the configurations of *P*, *M* (*MINT & MFRAC*) and *N* divider settings are stored the I<sup>2</sup>C register, and the configuration loaded at power-up is determined by the FSEL[1:0] pins

**Table 4 Frequency Selection** 

Input					
FSEL1 FSEL0		Selects	Register		
0 (def.)	0 (def.)	Frequency 0	P0, MINT0, MFRAC0, N0		
0	1	Frequency 1	P1, MINT1, MFRAC1, N1		
1	0	Frequency 2	P2, MINT2, MFRAC2, N2		
1	1	Frequency 3	P3, MINT3, MFRAC3, N3		

## Frequency Configuration

An order code is assigned to each frequency configuration programmed by the factory (default frequencies). For more information on the available default frequencies and order codes, please see the Ordering Information Section in this document. For available order codes, see the FemtoClock NG Ceramic-Package XO and VCXO Ordering Product Information document.

For more information and guidelines on programming of the device for custom frequency configurations, the register description, the pull range programming and the serial interface description, see the FemtoClock NG Ceramic 5x7 Module Programming Guide.

## **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>CC</sub>	3.63V
Inputs, V <sub>I</sub>	-0.5V to V <sub>CC</sub> + 0.5V
Outputs, I <sub>O</sub> (SDATA) Outputs, I <sub>O</sub> (LVPECL)	10mA
Continuous Current Surge Current	50mA 100mA
Package Thermal Impedance, $\theta_{JA}$	49.4°C/W (0 mps)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

### **DC Electrical Characteristics**

#### Table 5A. Power Supply DC Characteristics, $V_{CC}$ = 3.3V ± 5%, $V_{EE}$ = 0V, $T_A$ = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>CC</sub>	Positive Supply Voltage		3.135	3.3	3.465	V
I <sub>EE</sub>	Power Supply Current				150	mA

#### Table 5B. Power Supply DC Characteristics, $V_{CC}$ = 2.5V ± 5%, $V_{EE}$ = 0V, $T_A$ = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>CC</sub>	Positive Supply Voltage		2.375	2.5	2.625	V
I <sub>EE</sub>	Power Supply Current				145	mA

### Table 5C. LVPECL DC Characteristics, $V_{CC}$ = 3.3V $\pm$ 5% or $V_{CC}$ = 2.5V $\pm$ 5%, $V_{EE}$ = 0V, $T_A$ = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OH</sub>	Output High Voltage; NOTE 2		V <sub>CC</sub> – 1.3		V <sub>CC</sub> - 0.8	V
V <sub>OL</sub>	Output Low Voltage; NOTE 2		V <sub>CC</sub> – 2.0		V <sub>CC</sub> – 1.5	V
V <sub>SWING</sub>	Peak-to-Peak Output Voltage Swing		0.55		1.0	V

NOTE 1: Outputs terminated with  $50\Omega$  to  $\mbox{V}_{\mbox{CC}}$  – 2V.

Table 5D. LVCMOS/LVTTL DC Characteristic,  $V_{CC}$  = 3.3V  $\pm$  5% or 2.5V  $\pm$  5%,  $V_{EE}$  = 0V,  $T_A$  = -40°C to 85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
\/	Input Lligh Voltage	FSEL[1:0], OE	V <sub>CC</sub> = 3.3V +5%	1.7		V <sub>CC</sub> +0.3	V
$V_{IH}$	Input High Voltage	FSEL[1:0], OE	V <sub>CC</sub> = 2.5V +5%	1.7		V <sub>CC</sub> +0.3	V
		FSEL[1:0]	V <sub>CC</sub> = 3.3V +5%	-0.3		0.5	V
V	Input Low Voltage	OE	V <sub>CC</sub> = 3.3V +5%	-0.3		0.8	V
$V_{IL}$	Input Low Voltage	FSEL[1:0]	V <sub>CC</sub> = 2.5V +5%	-0.3		0.5	V
		OE	V <sub>CC</sub> = 2.5V +5%	-0.3	-0.3 0.8	0.8	V
		OE	$V_{CC} = V_{IN} = 3.465 \text{V or } 2.625 \text{V}$			10	μA
I <sub>IH</sub>	Input High Current	SDATA, SCLK	$V_{CC} = V_{IN} = 3.465 \text{V or } 2.625 \text{V}$			5	μA
		FSEL0, FSEL1	$V_{CC} = V_{IN} = 3.465 V \text{ or } 2.625 V$			150	μΑ
	Input Low Current	OE	V <sub>CC</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-500			μA
I <sub>IL</sub>		SDATA, SCLK	V <sub>CC</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-150			μA
		FSEL0, FSEL1	V <sub>CC</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-5		V <sub>CC</sub> +0.3 V <sub>CC</sub> +0.3 0.5 0.8 0.5 0.8 10	μA

#### **AC Electrical Characteristics**

Table 6A. VCXO Control Voltage Input (V<sub>C</sub>) Characterisitics,  $V_{CC} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $V_{EE} = 0V$ ,  $T_A = -40$ °C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
		ADC_GAIN[5:0] = 000001		7.57		ppm/V
	0 11 4 0 1 110777 4 0 0	ADC_GAIN[5:0] = 000010		15.15		ppm/V
	Oscillator Gain, NOTE 1, 2, 3 V <sub>CC</sub> = 3.3V	ADC_GAIN[5:0] = XXXXXX		25 · ADC_GAIN ÷ V <sub>CC</sub>		ppm/V
	100 0.01	ADC_GAIN[5:0] = 111110		469.69		ppm/V
K <sub>V</sub>		ADC_GAIN[5:0] = 111111		477.27		ppm/V
I'V		ADC_GAIN[5:0] = 000001		10		ppm/V
	O : NOTE 4 0 0	ADC_GAIN[5:0] = 000010		20		ppm/V
	Oscillator Gain, NOTE 1, 2, 3 V <sub>CC</sub> = 2.5V	ADC_GAIN[5:0] = XXXXXX		25 · ADC_GAIN ÷ V <sub>CC</sub>		ppm/V
	100 =.01	ADC_GAIN[5:0] = 111110		620		ppm/V
		ADC_GAIN[5:0] = 111111		630	7.57 pp 15.15 pp $\cdot$ ADC_GAIN $\div$ V <sub>CC</sub> pp 469.69 pp 477.27 pp 10 pp 20 pp $\cdot$ ADC_GAIN $\div$ V <sub>CC</sub> pp 620 pp 630 pp $\pm$ 0.1 +1	ppm/V
L <sub>VC</sub>	Control Voltage Linearity	BSL Variation; NOTE 4	-1	±0.1	+1	%
BW	Modulation Bandwidth			100		kHz
R <sub>VC</sub>	VC Input Resistance		500			kΩ
VC <sub>NOM</sub>	Nominal Control Voltage			V <sub>CC</sub> ÷2		V
V <sub>C</sub>	Control Voltage Tuning Range; NOTE 4		0		V <sub>CC</sub>	V

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1:  $V_C = 10\%$  to 90% of  $V_{CC}$ .

NOTE 2: Nominal oscillator gain: Pull range divided by the control voltage tuning range of 3.3V.

E.g. for ADC\_GAIN[6:0] = 000001 the pull range is ±12.5ppm, resulting in an oscillator gain of 25ppm ÷ 3.3V = 7.57ppm/V.

NOTE3: For best phase noise performance, use the lowest K<sub>V</sub> that meets the requirements of the application.

NOTE 4: BSL = Best Straight Line Fit: Variation of the output frequency vs. control voltage V<sub>C</sub>, in percent. V<sub>C</sub> ranges from 10% to 90% V<sub>CC</sub>.

Table 6B. AC Characteristics,  $V_{CC}$  = 3.3V ± 5% or 2.5V ± 5%,  $V_{EE}$  = 0V,  $T_A$  = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
£	Output Frequency Q, nQ	Output Divider, $N = 3 \text{ to } 126$	15.476		866.67	MHz
OUT	Output Frequency Q, fiQ	Output Divider, $N = 2$	975		1,300	MHz
f <sub>l</sub>	Initial Accuracy	Measured at 25°C			±10	ppm
		Option code = A or B			±100	ppm
$f_S$	Temperature Stability	Option code = E or F			±50	ppm
		Option code = K or L			866.67  1,300  ±10  ±100  ±50  ±20  ±3  ±5  ±113  ±63  ±33  20  4  0.990  0.757	ppm
4	Aging	Frequency drift over 10 year life			±3	ppm
<sup>I</sup> A	Aging	Frequency drift over 15 year life			±5	ppm
		Option code A or B (10 year life)			1,300 ±10 ±100 ±50 ±20 ±3 ±5 ±113 ±63 ±33 20 .85 4 475 0.990 487 0.757 614 72.0 99.0 25.7 29.5 40.5 44.4 54 425 55 20	ppm
fs  fA  fT  fjit(cc)  fjit(per)  fjit( $\emptyset$ ) $\Phi_N(100)$ $\Phi_N(10k)$ $\Phi_N(10k)$ $\Phi_N(100k)$ $\Phi_N(100k)$ $\Phi_N(100k)$ $\Phi_N(100k)$ $\Phi_N(100k)$ $\Phi_N(100k)$ $\Phi_N(100k)$	Total Stability	Option code E or F (10 year life)			±63	ppm
		Output Divider, N = 3 to126   15.476   866.67	ppm			
tjit(cc)	Cycle-to-Cycle Jitter; NOTE 1				20	ps
tjit(per)	RMS Period Jitter; NOTE 1			2.85	4	ps
	RMS Phase Jitter (Random) Fractional PLL feedback and			0.475	0.990	ps
<i>t</i> jit(Ø)	f <sub>XTAL</sub> =114.285MHz (0xxx order	f <sub>OUT</sub> = 156.25MHz, NOTE 2, 3, 4		0.487	866.67  1,300  ±10  ±100  ±50  ±20  ±3  ±5  ±113  ±63  ±33  20  4  0.990  0.757	ps
	codes)	f <sub>OUT</sub> = 156.25MHz, NOTE 2, 3, 5		0.614	1,300 ±10 ±100 ±50 ±20 ±3 ±5 ±113 ±63 ±33 20 4 0.990 0.757	ps
Φ <sub>N</sub> (100)	Single-side band phase noise, 100Hz from Carrier	156.25MHz		-72.0		dBc/Hz
Φ <sub>N</sub> (1k)	Single-side band phase noise, 1kHz from Carrier	156.25MHz		-99.0		dBc/Hz
Φ <sub>N</sub> (10k)	Single-side band phase noise, 10kHz from Carrier	156.25MHz		-125.7		dBc/Hz
Φ <sub>N</sub> (100k)	Single-side band phase noise, 100kHz from Carrier	156.25MHz		-129.5		dBc/Hz
Φ <sub>N</sub> (1M)	Single-side band phase noise, 1MHz from Carrier	156.25MHz		-140.5		dBc/Hz
Φ <sub>N</sub> (10M)	Single-side band phase noise, 10MHz from Carrier	156.25MHz		-144.4		dBc/Hz
PSNR	Power Supply Noise Rejection			-54		db
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	20% to 80%	100		425	ps
odc	Output Duty Cycle		45		55	%
tosc	Device startup time after power-up				20	ms
t <sub>SET</sub>	Output frequency settling time after FSEL0 and FSEL1 values are changed			470		μs

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions. All AC parameters are characterized with P=1 and pull range = ±250 ppm.

NOTE: XTAL parameters (initial accuracy, temperature stability, aging and total stability) are guaranteed by manufacturing.

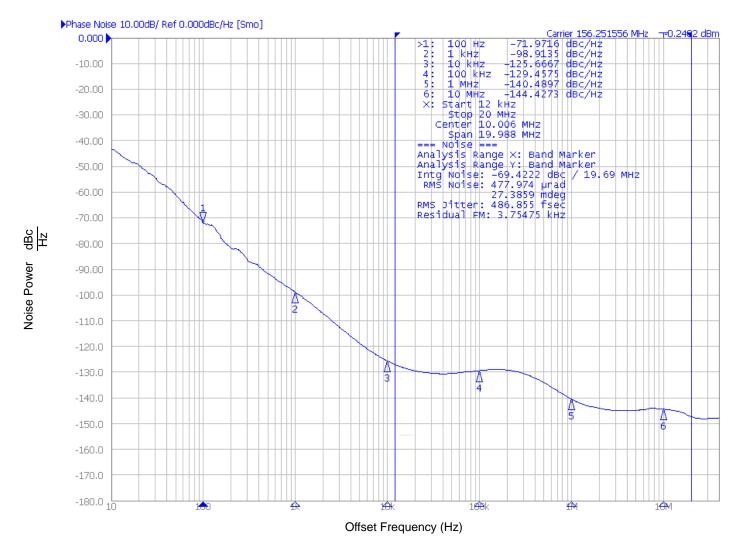
NOTE 1: This parameter is defined in accordance with JEDEC standard 65.

NOTE 2: Please refer to the phase noise plots.

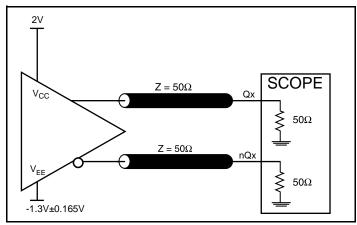
NOTE 3: Please see the FemtoClockNG Ceramic 5x7 Modules Programming guide for more information on finding the optimum configuration for phase noise.

NOTE 4: Integration range: 12kHz-20MHz. NOTE 5: Integration range: 1kHz-40MHz.

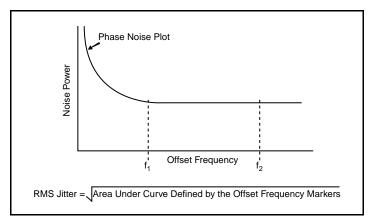
# Typical Phase Noise at 156.25MHz (12kHz - 20MHz)



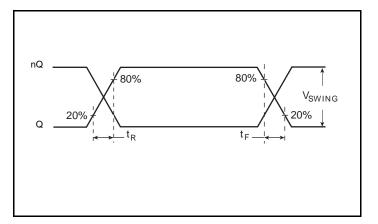
#### **Parameter Measurement Information**



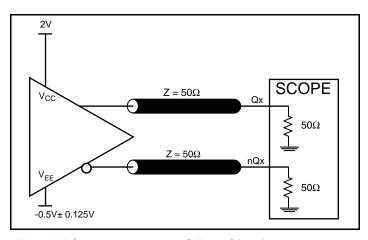
3.3V LVPECL Output Load AC Test Circuit



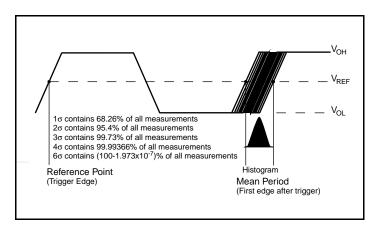
**RMS Phase Jitter** 



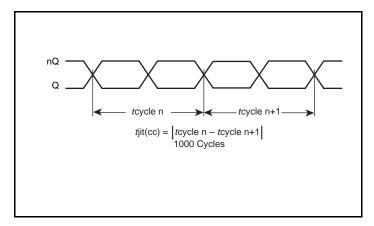
**Output Rise/Fall Time** 



2.5V LVPECL Output Load AC Test Circuit

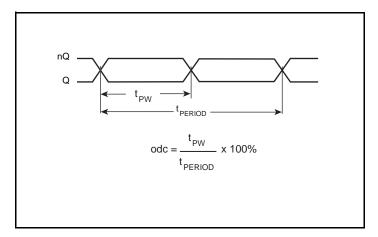


**Period Jitter** 

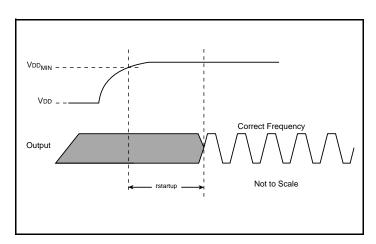


Cycle-to-Cycle Jitter

## **Parameter Measurement Information, continued**



Output Duty Cycle/Pulse Width/Period



**Start-Up Time** 

# **Applications Information**

## **Recommendations for Unused Input Pins**

## Inputs:

#### **LVCMOS Select Pins**

The FSEL[1:0] have internal pulldowns and the OE control pin has an internal pullup; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used. SCLK and SDATA should be left floating if not used.

#### **Termination for 3.3V LVPECL Outputs**

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

The differential outputs are low impedance follower outputs that generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to drive  $50\Omega$ 

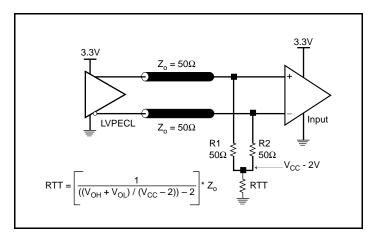


Figure 1A. 3.3V LVPECL Output Termination

transmission lines. Matched impedance techniques should be used to maximize operating frequency and minimize signal distortion. *Figures 1A and 1B* show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

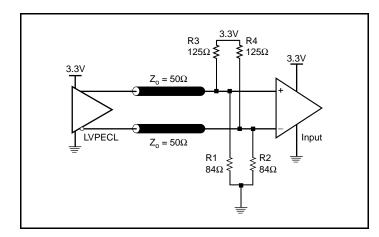


Figure 1B. 3.3V LVPECL Output Termination

## **Termination for 2.5V LVPECL Outputs**

Figure 2A and Figure 2B show examples of termination for 2.5V LVPECL driver. These terminations are equivalent to terminating  $50\Omega$ to  $V_{CC}$  – 2V. For  $V_{CC}$  = 2.5V, the  $V_{CC}$  – 2V is very close to ground

level. The R3 in Figure 2B can be eliminated and the termination is shown in Figure 2C.

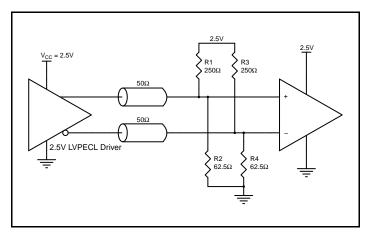
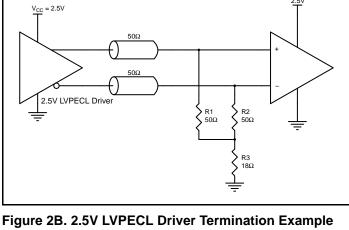


Figure 2A. 2.5V LVPECL Driver Termination Example



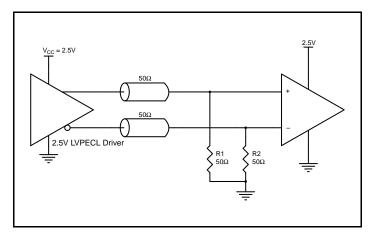


Figure 2C. 2.5V LVPECL Driver Termination Example

#### **Schematic Layout**

Figure 3 shows an example of IDT8N3QV01 application schematic. In this example, the device is operated at  $V_{CC} = 3.3V$ . As with any high speed analog circuitry, the power supply pins are vulnerable to noise. To achieve optimum jitter performance, power supply isolation is required. The IDT8N3QV01 provides separate power supplies to isolate from coupling into the internal PLL.

In order to achieve the best possible filtering, it is recommended that the placement of the filter components be on the device side of the PCB as close to the power pins as possible. If space is limited, the 0.1uF capacitor in each power pin filter should be placed on the device side of the PCB and the other components can be placed on the opposite side.

Power supply filter recommendations are a general guideline to be used for reducing external noise from coupling into the devices. The filter performance is designed for wide range of noise frequencies. This low-pass filter starts to attenuate noise at approximately 10kHz. If a specific frequency noise component is known, such as switching power supply frequencies, it is recommended that component values be adjusted and if required, additional filtering be added. Additionally, good general design practices for power plane voltage stability suggests adding bulk capacitances in the local area of all devices.

The schematic example focuses on functional connections and is not configuration specific. Refer to the pin description and functional tables in the datasheet to ensure the logic control inputs are properly set.

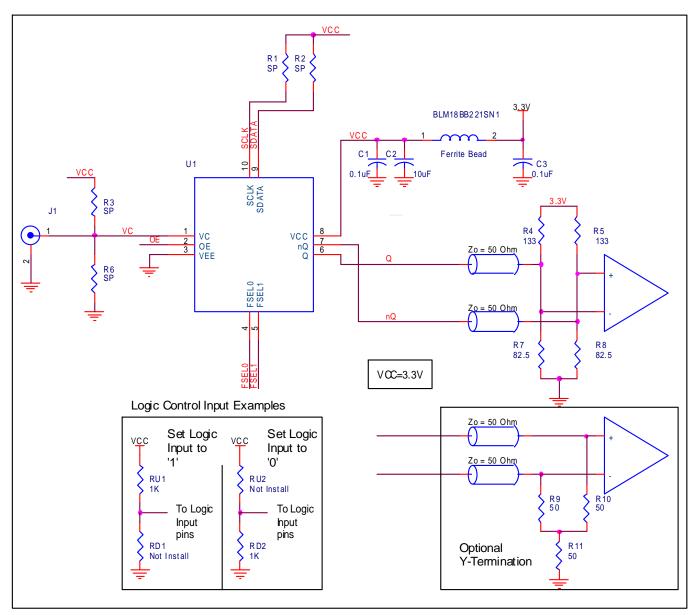


Figure 3. IDT8N3QV01 Application Schematic

#### **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS8N3QV01. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS8N3QV01 is the sum of the core power plus the power dissipation in the load(s). The following is the power dissipation for  $V_{CC} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

NOTE: Please refer to Section 3 for details on calculating power dissipation in the load.

- Power (core)<sub>MAX</sub> = V<sub>CC\_MAX</sub> \* I<sub>EE\_MAX</sub> = 3.465V \* 150mA = **519.75mW**
- Power (outputs)<sub>MAX</sub> = 34.2mW/Loaded Output pair

Total Power\_MAX (3.465V, with all outputs switching) = 519.75mW + 34.2mW = 533.95mW

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad, and directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature, Tj, to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA}$  \* Pd\_total + T<sub>A</sub>

Tj = Junction Temperature

 $\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

 $T_A$  = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 49.4°C/W per Table 7 below.

Therefore, Tj for an ambient temperature of 85°C with all outputs switching is:

 $85^{\circ}\text{C} + 0.554\text{W} * 49.4^{\circ}\text{C/W} = 112.4^{\circ}\text{C}$ . This is below the limit of  $125^{\circ}\text{C}$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

Table 7. Thermal Resistance  $\theta_{JA}$  for 10 Lead Ceramic 5mm x 7mm Package, Forced Convection

$\theta_{JA}$ by Velocity					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	49.4°C/W	44.2C/W	41°C/W		

#### 3. Calculations and Equations.

The purpose of this section is to calculate the power dissipation for the LVPECL output pair.

LVPECL output driver circuit and termination are shown in Figure 4.

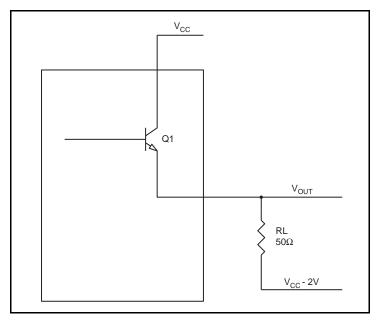


Figure 4. LVPECL Driver Circuit and Termination

To calculate worst case power dissipation into the load, use the following equations which assume a  $50\Omega$  load, and a termination voltage of  $V_{CC}$  – 2V.

- For logic high,  $V_{OUT} = V_{OH\_MAX} = V_{CC\_MAX} 0.8V$  $(V_{CC\_MAX} - V_{OH\_MAX}) = 0.8V$
- For logic low,  $V_{OUT} = V_{OL\_MAX} = V_{CC\_MAX} 1.5V$  $(V_{CC\_MAX} - V_{OL\_MAX}) = 1.5V$

Pd\_H is power dissipation when the output drives high.

Pd\_L is the power dissipation when the output drives low.

$$Pd_{-}H = [(V_{OH\_MAX} - (V_{CC\_MAX} - 2V))/R_{L}] * (V_{CC\_MAX} - V_{OH\_MAX}) = [(2V - (V_{CC\_MAX} - V_{OH\_MAX}))/R_{L}] * (V_{CC\_MAX} - V_{OH\_MAX}) = [(2V - 0.8V)/50\Omega] * 0.8V = 19.2mW$$

$$Pd_{L} = [(V_{OL\_MAX} - (V_{CC\_MAX} - 2V))/R_{L}] * (V_{CC\_MAX} - V_{OL\_MAX}) = [(2V - (V_{CC\_MAX} - V_{OL\_MAX}))/R_{L}] * (V_{CC\_MAX} - V_{OL\_MAX}) = [(2V - 1.5V)/50\Omega] * 1.5V = 15mW$$

Total Power Dissipation per output pair = Pd\_H + Pd\_L = 34.2mW

# **Reliability Information**

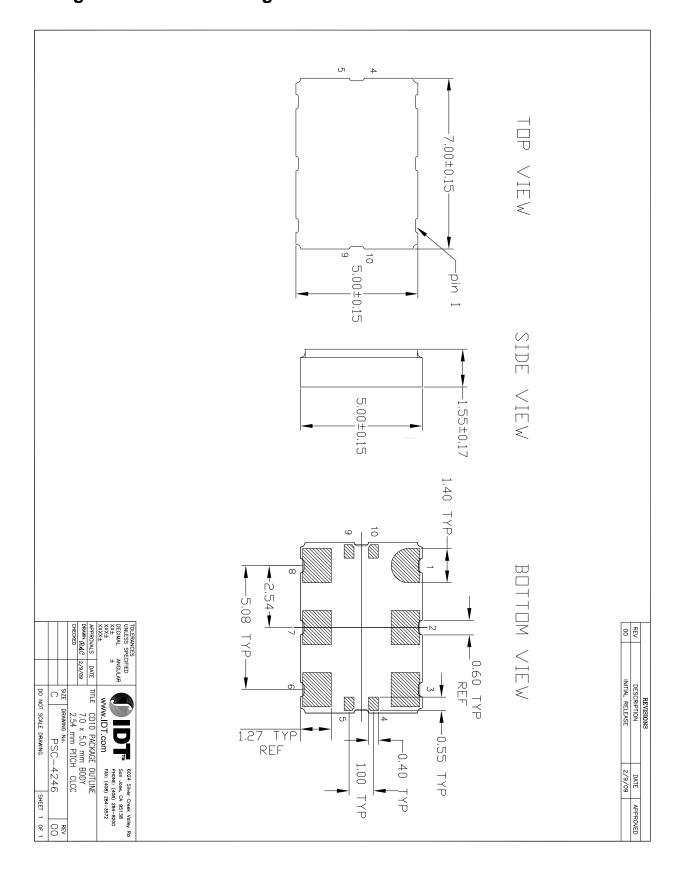
## Table 8. $\theta_{\text{JA}}$ vs. Air Flow Table for a 10-lead Ceramic 5mm x 7mm Package

$\theta_{JA}$ vs. Air Flow					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	49.4°C/W	44.2C/W	41°C/W		

#### **Transistor Count**

The transistor count for IDT8N3QV01 Rev G is: 43, 718

# **Package Outline and Package Dimensions**

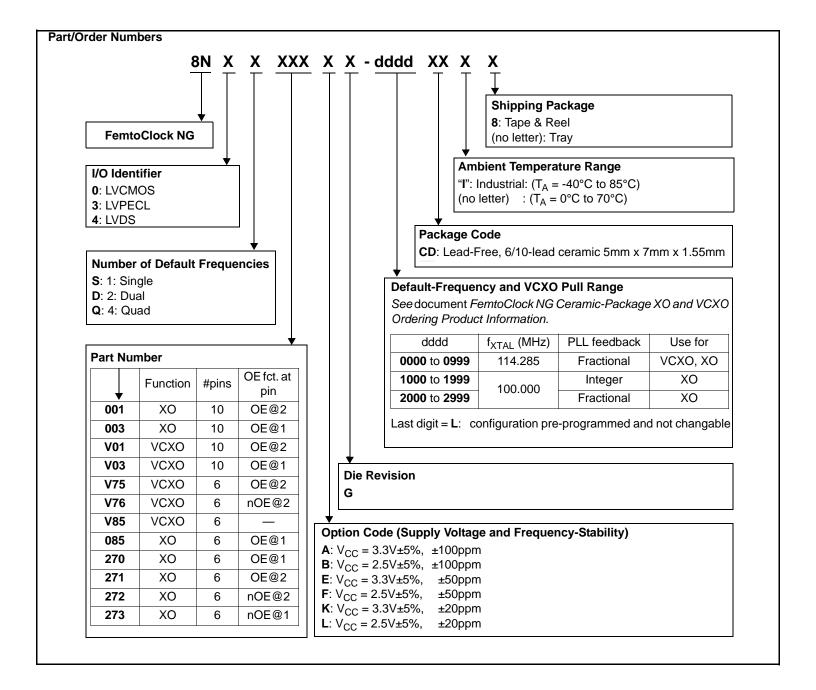


## Ordering Information for FemtoClock NG Ceramic-Package XO and VCXO Products

The programmable VCXO and XO devices support a variety of devices options such as the output type, number of default frequencies, internal crystal frequency, power supply voltage, ambient temperature range and the frequency accuracy. The device options, default frequencies and default VCXO pull range must be specified at the time of order and are programmed by IDT before the shipment. The table below specifies the available order codes, including the device options and default frequency configurations. Example part number: the order code 8N3QV01FG-0001CDI specifies a programmable, quad default-frequency VCXO with a voltage supply of 2.5V, a LVPECL output, a ±50 ppm crystal frequency accuracy,

contains a 114.285MHz internal crystal as frequency source, industrial temperature range, a lead-free (6/6 RoHS) 10-lead Ceramic 5mm x 7mm x 1.55mm package and is factory-programmed to the default frequencies of 100, 122.88, 125 and 156.25MHz and to the VCXO pull range of min.  $\pm 100$  ppm.

Other default frequencies and order codes are available from IDT on request. For more information on available default frequencies, see the FemtoClock NG Ceramic-Package XO and VCXO Ordering Product Information document.



## **Table 9. Device Marking**

Marking	Industrial Temperature Range (T <sub>A</sub> = -40°C to 85°C)	Commercial Temperature Range (T <sub>A</sub> = 0°C to 70°C)	
	IDT8N3xV01 <b>y</b> G-	IDT8N3 <b>x</b> V01 <b>y</b> G-	
	<b>dddd</b> CDI	<b>dddd</b> CD	
	x = Number of Default Frequencies, y = Option Code, dddd=Default-Frequency and VCXO Pull Range		

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# **Revision History Sheet**

Rev	Table	Page	Description of Change	Date
Α	9	21	Table 9 Device Marking, corrected marking.	3/6/12

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